



N-Channel Reduced Qg, Fast Switching MOSFET

Characteristics

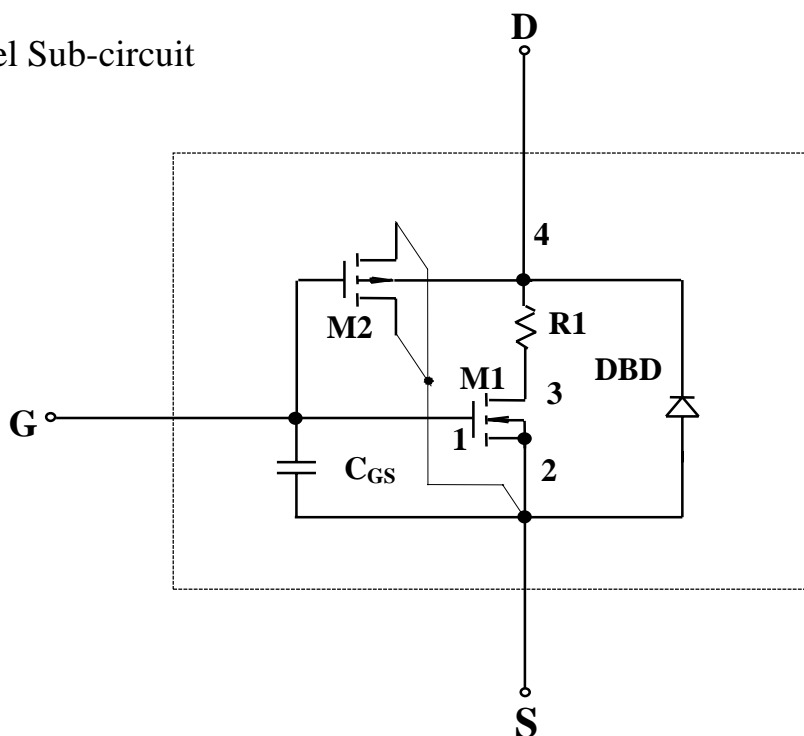
- N-channel Vertical DMOS
- Macro-Model (Sub-circuit)
- Level 3 MOS
- Applicable for Both Linear and Switch Mode
- Applicable Over a -55 to 125°C Temperature Range
- Models Gate Charge, Transient, and Diode Reverse Recovery Characteristics

Description

The attached SPICE Model describes typical electrical characteristics of the n-channel vertical DMOS. The sub-circuit model was extracted and optimized over a 25°C to 125°C temperature range under pulse conditions for 0 to 10 volt gate drives. Saturated output impedance model accuracy has been maximized for gate biases near threshold. A novel gate-to-drain feedback

capacitor network is used to model gate charge characteristics while avoiding convergence problems of switched C_{gd} model. Model parameter values are optimized to provide a best fit to measure electrical data and are not intended as an exact physical description of a device.

Model Sub-circuit



This document is intended as a SPICE modeling guideline and does not constitute a commercial product data sheet. Designers should refer to the appropriate data sheet of the same number for guaranteed specification limits.



SPICE Device Model Si4850EY

Model Evaluation

N-Channel Device ($T_J=25^{\circ}\text{C}$ Unless Otherwise Noted)

Parameter	Symbol	Test Conditions	Typical	Unit
Static				
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	1.95	V
On-State Drain Current ^a	$I_{D(on)}$	$V_{DS} \geq 5\text{V}, V_{GS} = 10\text{V}$	248	A
Drain-Source On-State Resistance ^a	$r_{DS(on)}$	$V_{GS} = 10\text{V}, I_D = 6\text{A}$ $V_{GS} = 10\text{V}, I_D = 6\text{A},$ $T_J = 125^{\circ}\text{C}$ $V_{GS} = 10\text{V}, I_D = 6\text{A},$ $T_J = 175^{\circ}\text{C}$ $V_{GS} = 4.5\text{V}, I_D = 5.1\text{A}$	0.017 0.026 0.032 0.023	Ω
Forward Transconductance ^a	g_{fs}	$V_{DS} = 15\text{V}, I_D = 6\text{A}$	22	S
Diode Forward Voltage ^a	V_{SD}	$I_S = 1.7\text{A}, V_{GS} = 0\text{V}$	0.80	V
Dynamic ^b				
Total Gate Charge	Q_g	$V_{DS} = 30\text{V}, V_{GS} = 10\text{V},$ $I_D = 6\text{A}$	17.5	nC
Gate-Source Charge	Q_{gs}		3.4	
Gate-Drain Charge	Q_{gd}		5.3	
Turn-On Delay Time	$t_{d(on)}$	$V_{DD} = 30\text{V}, R_L = 30\Omega$ $I_D \cong 1\text{A}, V_{GEN} = 10\text{V},$ $R_G = 6\Omega$	22	ns
Rise Time	t_r		25	
Turn-Off Delay Time	$t_{d(off)}$		42	
Fall Time	t_f		48	
Source-Drain Reverse Recovery Time	trr	$I_F = 1.7\text{A } di/dt = 100\text{A}/\mu\text{s}$	39	

Notes:

- a) Pulse test; pulse width $\leq 300 \mu\text{sec}$, duty cycle $\leq 2\%$
- b) Guaranteed by design, not subject to production testing



SPICE Device Model Si4850EY

Comparison of Model with Measured Data
($T_J=25^\circ\text{C}$ Unless Otherwise Noted)

